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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/682,508	10/10/2003	Toshiaki Iwata	SUZU.0003	9882

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EXAMINER
CHAN, EMILY Y

ART UNIT	PAPER NUMBER
2829	

DATE MAILED: 07/29/2004

Please find below and/or attached an Office communication concerning this application or proceeding.

Office Action Summary	**Application No.** 10/682,508	**Applicant(s)** IWATA ET AL.	
	Examiner Emily Y Chan	**Art Unit** 2829	

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --

Period for Reply

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If the period for reply specified above is less than thirty (30) days, a reply within the statutory minimum of thirty (30) days will be considered timely.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

Status

1)☒ Responsive to communication(s) filed on *10 October 2003*.
2a)☐ This action is **FINAL**. 2b)☒ This action is non-final.
3)☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

Disposition of Claims

4)☒ Claim(s) *1-7* is/are pending in the application.
 4a) Of the above claim(s) _____ is/are withdrawn from consideration.
5)☒ Claim(s) *4 and 5* is/are allowed.
6)☒ Claim(s) *1-3,6 and 7* is/are rejected.
7)☐ Claim(s) _____ is/are objected to.
8)☐ Claim(s) _____ are subject to restriction and/or election requirement.

Application Papers

9)☐ The specification is objected to by the Examiner.
10)☐ The drawing(s) filed on _____ is/are: a)☐ accepted or b)☐ objected to by the Examiner.
 Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).
 Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).
11)☐ The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.

Priority under 35 U.S.C. § 119

12)☒ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
 a)☒ All b)☐ Some * c)☐ None of:
  1.☒ Certified copies of the priority documents have been received.
  2.☐ Certified copies of the priority documents have been received in Application No. _____.
  3.☐ Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).
 * See the attached detailed Office action for a list of the certified copies not received.

Attachment(s)

1) ☒ Notice of References Cited (PTO-892)
2) ☐ Notice of Draftsperson's Patent Drawing Review (PTO-948)
3) ☒ Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08)
 Paper No(s)/Mail Date _____.
4) ☐ Interview Summary (PTO-413)
 Paper No(s)/Mail Date. _____ .
5) ☐ Notice of Informal Patent Application (PTO-152)
6) ☐ Other: _____.

DETAILED ACTION

Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

> (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

1. Claims 1-3 and 6-7 are rejected under 35 U.S.C. 103(a) as being unpatentable over Ando et al (JP-11-014957) in view of Toshiaki Iwata (JP-08-189946).

Regarding to claims 1 and 7, Ando et al (JP-11-014957) disclose inspection device for liquid crystal panel (see Fig. 5,10) and expressly teach the invention as claimed, comprising:

a rotary base (slider 96) having a surface on which a display panel (12) is to be placed, and a rotation shaft (60, 62, 68, and 70) inclined with respect to a horizontal;

a fixture base (30, 32, 34) having a driving section, which rotates the rotation shaft (60, 62, 68, 70), and supporting the rotary base (slider 96) to be rotatable about the rotation shaft (60, 62, 68, 70);

a Z-axis drive mechanism (See Abstract, SOLUTION, Fig. 18, driving source 114 and DETAILED DESCRPTION, PARAGRAPH 0054), which moves the fixture base (30, 32, 34) forward toward the front of the display panel inspection apparatus to a predetermined position (inspection position) and backward to be retracted;

a probe unit (40) which face the surface of the rotary base (96) that is at the front position when the fixture base (30,32,34) is moved to the predetermined position (inspection position) by the Z-axis drive mechanism (Fig. 18, driving source 114) and

an X-, Y-, and theta axes adjustment stage device (see DETAILED DESCRPTION, paragraph 0038) which position-controls the probe unit (40) to achieve poisoning between the probe unit (40) and the display panel (12).

Ando et al (JP-11-014957) do not disclose that their rotary base (slider 96) having first and second surfaces on which display panels are to be placed and the first and second surfaces can be switched between a front position and a top position facing upward.

Toshiaki Iwata (JP08-189946) discloses an electronic board body inspecting device (see Fig. 1) and exclusively teaches a rotary base (slider 100) having first and second surfaces (101, 102) on which display panels (see Fig. 5a, 5b, 500, 501) are to be placed. Furthermore, Toshiaki Iwata (JP08-189946) teaches that their first and second surfaces (101, 102) can be switched between the front position (inspection location) and a top position facing upward (supply location) (see Abstract, CONSTITUTION).

It would have been obvious to one of ordinary skill in the art at the time the claimed invention was made to incorporate the feature of switching the first display panels already inspected with the second display panel to be inspected next as taught by Toshiaki Iwata (JP08-189946) into Ando et al (JP-11-014957)'s panel inspection device for the expected benefit of remarkably improving the workability and shorten the working time as disclosed by Toshiaki Iwata (JP08-189946) (see abstract, PURPOSE).

2. Regarding to clam 2, Ando et al (JP-11-014957) teach a pallet device (72, 102) having a backlight (58).

3. Regarding to clam 3, Ando et al (JP-11-014957) teach a front panel having a window (44, 46, 48) and a stage device (44) attached to surround the window (44, 46, 48) of the front panel (see Fig. 5).

4. Regarding to claim 6, Ando et al (JP-11-014957) disclose a display panel inspection method using a display panel inspection apparatus comprising: a rotary base (96), a rotation shaft (60, 62, 68, and 70), a fixture base (30, 32, and 34), a Z-axis drive mechanism (driving source 114) and a probe unit (40) (see paragraph 1 above), the method comprising:

inspecting a first display panel (12) on the facing position (inspection location) of the rotary base (96) by the probe unit (40);

after completion of the first display panel (12), retreating the fixture base (30, 32, 34) by the Z-axis drive mechanism (driving source 114); and

rotating the rotary base (96) to inspect the second display panel (12).

Ando et al (JP-11-014957) do not disclose that their rotary base (slider 96) has first and second surfaces on which display panels are to be placed and the first and second surfaces can be switched between a front position and a top position facing upward. Ando et al (JP-11-014957) also do not disclose the step of exchanging a display panel on the top position, which has been inspected, with a second display panel to be inspected next.

Toshiaki Iwata (JP08-189946) discloses an electronic board body inspecting device (see Fig. 1) and exclusively teach a rotary base (slider 100) having first and second surfaces (101, 102) on which display panels (see Fig. 5a, 5b, 500, 501) are to be placed and their first and second surfaces (101, 102) can be switched between the a front position (inspection location) and a top position facing upward (supply location. Moreover. Toshiaki Iwata (JP08-189946) teaches the step of exchanging a display panel on the top position during the inspection, which has been inspected, with a second display panel to be inspected next (see abstract, CONSTITUTION).

It would have been obvious to one of ordinary skill in the art at the time the claimed invention was made to incorporate the feature of exchanging the display panel already inspected with the second display panel to be inspected next as taught by Toshiaki Iwata (JP08-189946) into Ando et al (JP-11-014957)'s panel inspection device for the expected benefit of remarkably improving the workability and shorten the working time as disclosed by Toshiaki Iwata (JP08-189946) (see abstract, PURPOSE).

Allowable Subject Matter

5. Claims 4-5 are allowed.

The following is a statement of reasons for the indication of allowable subject matter.

Claims 4-5 are indicated allowable because the claimed features that the rotary base has three surfaces and has a substantially triangular cross section including first, second and third sides in a side view related to the display panel inspection area are not taught or suggested by the prior art.

The prior art made of record and not relied upon is considered pertinent to applicant's disclosure.

Hirai et al (JP2000-147044) disclose a device and method for inspecting plate-shaped object and teach x-stage, y-stage, z-stage and theta stage drive mechanism.

Lino et al ('500) disclose an unit for transferring to-be- inspected flat display panel to an inspection position.

Hirasawa (JP2000-321545) discloses a liquid crystal panel inspection apparatus and teach treating a plurality of liquid crystal panels in parallel and shorting the time for inspection of the liquid crystal panels.

Takekoshi et al ('764) disclose an apparatus for examining LCD panels and teach x-stage, y-stage z-stage and theta stage drive mechanism (see Col. 5, line 67) and a back light (see Col. 6, line 64).

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Emily Y Chan whose telephone number is 5712721956. The examiner can normally be reached on 8:30-5:30.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Cuneo Kammie can be reached on 5712721957. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Ec
7-20-04

DAVID ZARNEKE
PRIMARY EXAMINER
7/21/04